

Editorial

The first issue of *Microscopy, Microanalysis, Microstructures* appeared in early 1990. We are therefore in the sixth year of publication of this successor of the *Journal de Microscopie et Spectroscopie Electroniques*. The main objective of MMM is to provide a platform for the publication of original papers on the use of the latest methods and techniques in all kinds of microscopies for solving structural and chemical problems in Materials Science. The development of tools in Electron and Photon Microscopies, Electron, X-ray and Ion Microanalysis, Local Probe Microscopies and Spectroscopies for the investigation of the micro- and nanoscale properties of solid materials is therefore particularly emphasized.

Over the last five years, MMM has published 234 manuscripts, about 90% of them written in English, with 58% of them originating from France and 42% from foreign laboratories, mostly located in Japan, Sweden, USA, Germany and UK. Most of the opening outside France has been due to the publication of special issues devoted to special topics. Let us recall the following special issues: *Atomic level microstructure of inorganic solids and their surfaces* (Vol. 1, 5-6, 1990 with L. Kihlborg and R. Portier as guest editors); *Proceedings of Lake Tahoe Workshop on Electron Energy Loss Spectroscopy* (Vol. 2, 2-3, 1991 with O.L. Krivanek as guest editor); *Special issue dedicated to Prof. Raimond Castaing for his 70th birthday* (Vol. 3, 2-3, 1992 with C. Colliex as guest editor); *Proceedings of the French-Japanese Seminar on In Situ Electron Microscopy* (Vol. 4, 2-3, 1993 with F. Louchet and H. Saka as guest editors). These volumes constitute, as a matter of fact, an attractive window of selected topics in the general fields covered by the journal and have largely contributed to the rapid growth of its impact factor measured in the Journal Citation Reports, bringing it within two years at the level of the major international journals dealing with microscopy and applications.

We feel therefore that the publication is now becoming mature and that it is time to stabilize its international coverage and to broaden the range of subjects. Consequently the editorial board has been widened with the editors listed below having agreed to join us. This worldwide representation will also assist in speeding up the processing of manuscripts before publication because all editors share the responsibility of accepting or rejecting them. Original research papers dealing with all aspects of microscopy and microanalysis and their use in materials science, can therefore be submitted to any Editor.

The change in Editorial policy will become effective in January 1996, but I urge you to use this new procedure from now in order to fill quickly the first issues of MMM, volume 7 (1996).